

March 2013

FDD390N15ALZ

N-Channel PowerTrench[®] MOSFET 150 V, 26 A, 42 m Ω

Features

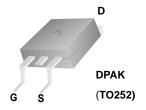
- $R_{DS(on)} = 33.4 \text{ m}\Omega$ (Typ.) @ $V_{GS} = 10 \text{ V}$, $I_D = 26 \text{ A}$
- $R_{DS(on)}$ = 42.2 m Ω (Typ.) @ V_{GS} = 4.5 V, I_D = 20 A
- · Fast Switching Speed
- Low gate charge, QG = 17.6 nC (Typ.)
- \bullet High Performance Trench Technology for Extremely Low $R_{\text{DS(on)}}$
- · High Power and Current Handling Capability
- · RoHS Compliant

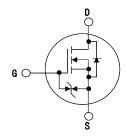
Description

This N-Channel MOSFET is produced using Fairchild Semiconductor[®]'s advanced PowerTrench[®] process that has been tailored to minimize the on-state resistance while maintaining superior switching performance.

Applications

- Consumer Applicances
- LED TV
- · Synchronous Rectification
- Uninterruptible Power Supplies
- Micro Solar Inverter





MOSFET Maximum Ratings T_C = 25°C unless otherwise noted*

Symbol		Parameter		FDD390N15ALZ	Unit
V _{DSS}	Drain to Source Voltage			150	V
V_{GSS}	Gate to Source Voltage			±20	V
	Drain Current	- Continuous (T _C = 25°C)		26	А
ID	Drain Current	- Continuous (T _C = 100°C)		17	_ A
I _{DM}	Drain Current	- Pulsed	(Note 1)	104	Α
E _{AS}	Single Pulsed Avalanche Ener	gy	(Note 2)	96	mJ
dv/dt	Peak Diode Recovery dv/dt		(Note 3)	13	V/ns
D	Davies Dissipation	$(T_C = 25^{\circ}C)$		63	W
P_{D}	Power Dissipation	- Derate above 25°C		0.5	W/°C
T _J , T _{STG}	Operating and Storage Tempe	rature Range		-55 to +150	°C
TL	Maximum Lead Temperature f 1/8" from Case for 5 Seconds	Maximum Lead Temperature for Soldering Purpose,			°C

Thermal Characteristics

Symbol	Parameter	Min.	Max.	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case	-	2.0	°C/W
R _{0JA} Thermal Resistance, Junction to Ambient		-	87	30/00

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDD390N15ALZ	FDD390N15ALZ	D-PAK	380mm	16mm	2500

Electrical Characteristics $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
Off Charac	cteristics					
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	150	-	-	V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	I _D = 250μA, Referenced to 25°C	-	0.15	-	V/°C
1	Zero Gate Voltage Drain Current	V _{DS} = 120V, V _{GS} = 0V	-	-	1	μА
IDSS	Zero Gate voltage Drain Current	$V_{DS} = 120V, T_{C} = 125^{\circ}C$	-	-	500	μΑ
I _{GSS}	Gate to Body Leakage Current	$V_{GS} = \pm 20V, V_{DS} = 0V$	-	-	±10	μА

On Characteristics

V _{GS(th)}	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	1.4	•	2.8	٧
D	Static Drain to Source On Resistance	$V_{GS} = 10V, I_D = 26A$	•	33.4	42	mΩ
R _{DS(on)}	Static Drain to Source On Resistance	$V_{GS} = 4.5V, I_D = 20A$	-	42.2	64	mΩ
9 _{FS}	Forward Transconductance	$V_{DS} = 10V, I_{D} = 26A$	-	50	-	S

Dynamic Characteristics

C _{iss}	Input Capacitance	751/1/	0) /	-	1323	1760	pF
C _{oss}	Output Capacitance	V _{DS} = 75V, V _{GS}	; = 0V	-	93	120	pF
C _{rss}	Reverse Transfer Capacitance	1 - 1111112		-	4	6	pF
C _{oss(er)}	Energy Related Output Capacitance	$V_{DS} = 75V, V_{GS}$	= 0V	-	165	-	pF
Q _{g(tot)}	Total Gate Charge at 10V	V _{GS} = 10V	V _{DS} = 75V	-	17.6	39	nC
Q _{g(tot)}	Total Gate Charge at 5V	$V_{GS} = 4.5V$	I _D = 26A	-	8.1	10.5	nC
Q_{gs}	Gate to Source Gate Charge			-	4.7	-	nC
Q _{gd}	Gate to Drain "Miller" Charge		(Note 4)	-	2.3	-	nC
ESR	Equivalent Series Resistance (G-S)	f = 1MHz		-	1.48	-	Ω

Switching Characteristics

t _{d(on)}	Turn-On Delay Time			-	12.8	35.6	ns
t _r	Turn-On Rise Time	$V_{DD} = 75V, I_D = 26A$		-	9.3	28.6	ns
t _{d(off)}	Turn-Off Delay Time	$V_{GS} = 10V, R_{GEN} = 4.7\Omega$		-	26.9	63.8	ns
t _f	Turn-Off Fall Time		(Note 4)	-	3.2	16.4	ns

Drain-Source Diode Characteristics

I _S	Maximum Continuous Drain to Source Dioc	Maximum Continuous Drain to Source Diode Forward Current		-	26	Α
I _{SM}	Maximum Pulsed Drain to Source Diode Forward Current		-	-	104	Α
V_{SD}	Drain to Source Diode Forward Voltage	$V_{GS} = 0V, I_{SD} = 26A$	-	-	1.25	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0V, I _{SD} = 26A	-	70	-	ns
Q _{rr}	Reverse Recovery Charge	$dI_{F}/dt = 100A/\mu s$	-	169	-	nC

Notes:

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature
- 2. L = 3mH, I_{AS} = 6.75A, Starting T_J = 25°C
- 3. $I_{SD} \le 26 \text{A}, \ di/dt \le 200 \text{A}/\mu \text{s}, \ V_{DD} \le BV_{DSS}, \ Starting \ T_J = 25^{\circ}C$
- 4. Essentially Independent of Operating Temperature Typical Characteristics

Typical Performance Characteristics

Figure 1. On-Region Characteristics

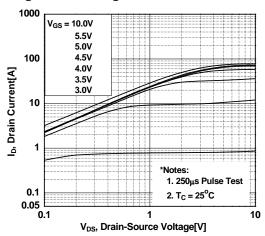


Figure 3. On-Resistance Variation vs.
Drain Current and Gate Voltage

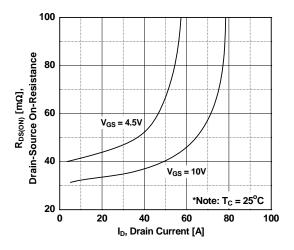


Figure 5. Capacitance Characteristics

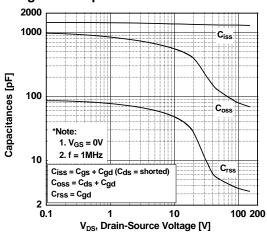


Figure 2. Transfer Characteristics

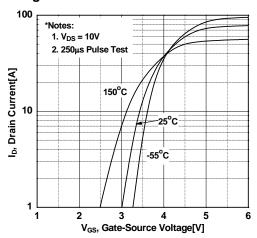


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

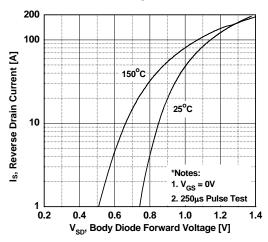
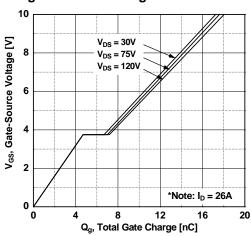
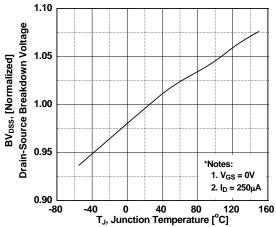


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature



, | ,A

Figure 8. On-Resistance Variation vs. Temperature

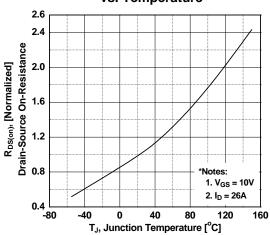


Figure 9. Maximum Safe Operating Area vs. Case Temperature

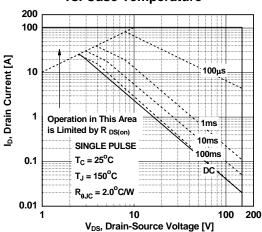


Figure 10. Maximum Drain Current

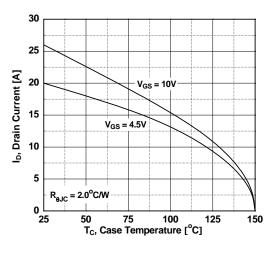


Figure 11. Eoss vs. Drain to Source Voltage

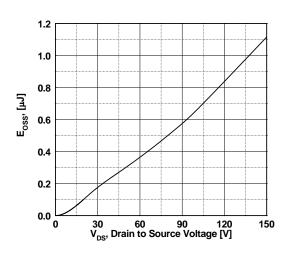
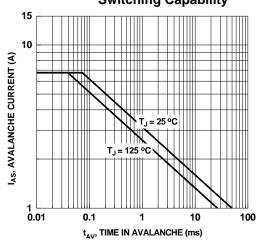
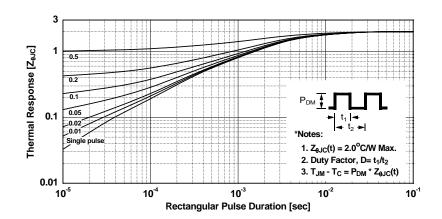


Figure 12. Unclamped Inductive Switching Capability

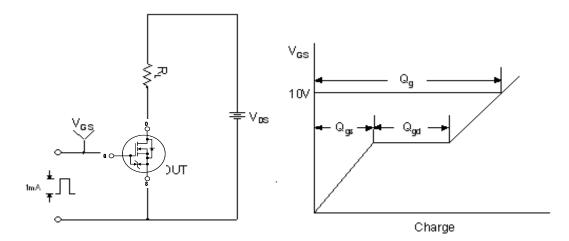


Typical Performance Characteristics (Continued)

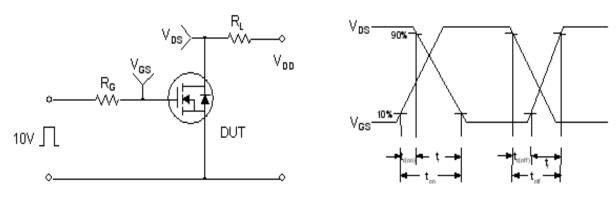
Figure 13. Transient Thermal Response Curve



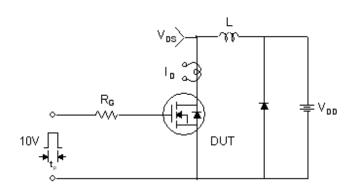
Gate Charge Test Circuit & Waveform

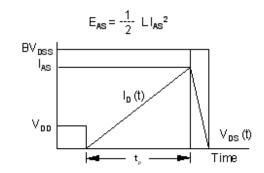


Resistive Switching Test Circuit & Waveforms

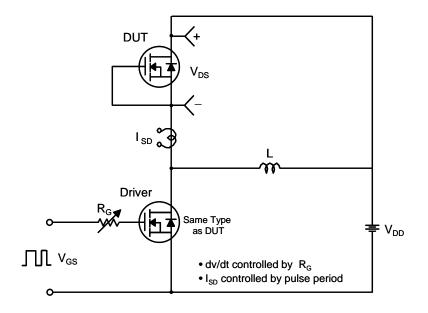


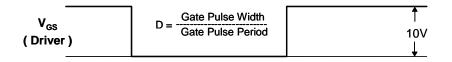
Unclamped Inductive Switching Test Circuit & Waveforms

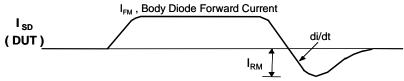




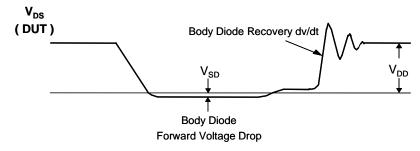
Peak Diode Recovery dv/dt Test Circuit & Waveforms





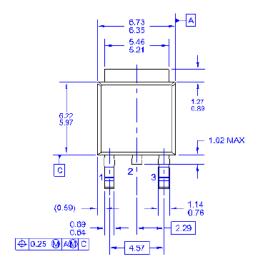


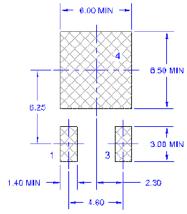
Body Diode Reverse Current



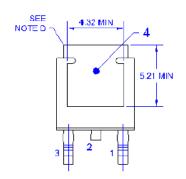
Mechanical Dimensions

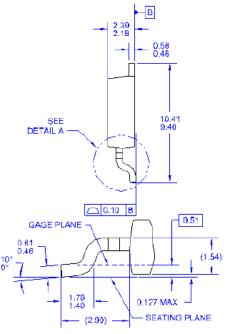
D-PAK





LAND PATTERN RECOMMENDATION





- NOTES: LINLESS OTHERWISE SPECIFIED

 A) THIS PACKAGE CONFORMS TO JEDEC, TO-252.
 ISSUE C, VARIATION AA.

 B) ALL DINEMSIONS ARE IN MILLIMETERS.
 C) DINEMSIONING AND TOLEMANCING PER
 ASME Y14.5M-1994.
 D) HEAT SINK TOP EDGE COULD BE IN CHAMFERED
 CORNERS OR EDGE FROTRUSION.
 E) PRESENCE OF TRIMMED CENTER LEAD
 IS OPTIONAL
 F) DIMENSIONS ARE EXCLUSRIVE OF BURSS,
 MOLD FLASH AND THE BAR EXTRUSIONS.
 B) LAND PATTERN RECOMENDATION IS BASED ON IPC7351A STD
 TO220P1003X295-3N.
- TO220P1009X239-3N.
 H: DRAWING NUMBER AND REVISION: WKT-TO252A03REVB

Dimensions in Millimeters





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CorePOWER™ Green FPS™ e-Series™ CROSSVOLTTM Gmax™

GTO™ $\mathsf{CTL^{\mathsf{TM}}}$ Current Transfer Logic™ IntelliMAX™ DEUXPEED® ISOPLANAR™

Dual Cool™ Marking Small Speakers Sound Louder

EcoSPARK® and Better™ MegaBuck™ EfficentMax™ ESBC™ MICROCOUPLER™ MicroFET™

MicroPak™ MicroPak2™ Fairchild[®] MillerDrive™ Fairchild Semiconductor® $MotionMax^{TM}$ FACT Quiet Series™ mWSaver™ OptoHiT™

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Programmable Active Droop™

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Datasheet Identification	Product Status	Definition
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No Identification Needed Full Production		Datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.
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